

SENSORS PRODUCT LINE TEST PROCEDURES

TYPICAL TEST PROCEDURES USED BY MICRO-MEASUREMENTS FOR APPROPRIATE SENSOR PRODUCTS		
Optical Defect Analysis :	Micro-Measurements Procedures and Standards	Test Frequency: Per batch
Gage Resistance at 24°C and 50%RH:	Micro-Measurements Procedures, National Institute of Standards and Technology Traceable Resistance Standards	Test Frequency: Per batch
Gage Thickness :	Micro-Measurements Procedures	Test Frequency: Per batch
Gage Factor at 24°C and 50%RH:	ASTM International E 251	Test Frequency: Per foil lot and gage pattern
Transverse Sensitivity at 24°C and 50%RH :	ASTM International E 251	Test Frequency: Per foil lot and gage pattern
Temperature Coefficient of Gage Factor :	ASTM International E 251	Test Frequency: Per foil lot
Thermal Output :	ASTM International E 251	Test Frequency: Per foil lot
Fatigue Life :	ASTM International E 1949	Test Frequency: Per gage series
Strain Limits :	National Aerospace Standard-942 Modified	Test Frequency: Per gage series
Creep and Drift :	Micro-Measurements Procedures, similar to NAS 942	Test Frequency: As needed (Transducer Class gages only)

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